

SCOPE :

This specification applies to the Pb Free high current type SMD inductors for
MSCD-32-SERIES

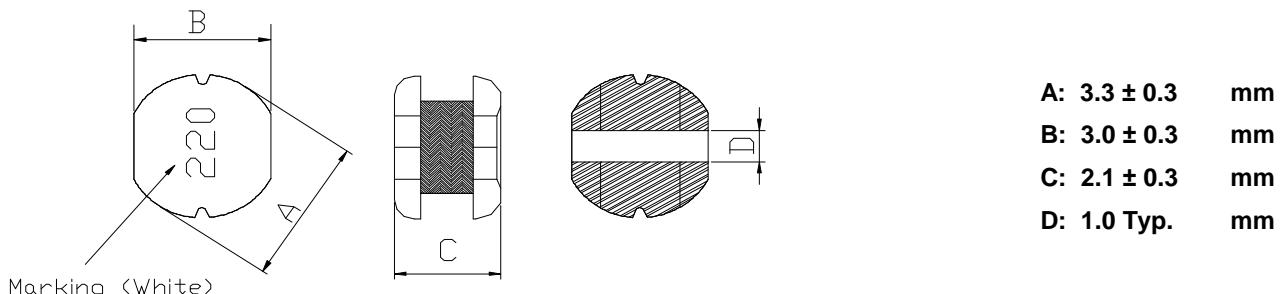
PRODUCT IDENTIFICATION

MSCD - 32 - 100 K-RU

① ② ③ ④

- ① Product Code
- ② Dimensions Code
- ③ Inductance Code
- ④ Tolerance Code

(1) SHAPES AND DIMENSIONS



(2) ELECTRICAL SPECIFICATIONS

SEE TABLE 1

TEST INSTRUMENTS

L : HP 4284A PRECISION LCR METER (or equivalent)

RDC : CHROMA MODEL 16502 MILLIOHMMETER (or equivalent)

(3) CHARACTERISTICS

- (3)-1 Ambient temperature +60°C Max.
- (3)-2 Operate temperature range -40°C ~ +125°C
(Including self temp. rise)
- (3)-3 Storage temperature range -40°C ~ +125°C



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TABLE 1

MAGLAYERS PT/NO.	Inductance L(μH)	Percent Tolerance	Test Frequency	Resistance RDC(Ω)Max.	Rated DC Current IDC(A)	Marking
MSCD-32-R47□-RU	0.47	N	100kHz/0.25V	17.7m	3.00	R47
MSCD-32-1R0□-RU	1.0	M,N	100kHz/0.25V	70m	2.08	1R0
MSCD-32-1R4□-RU	1.4	M,N	100kHz/0.25V	90m	1.86	1R4
MSCD-32-1R5□-RU	1.5	M,N	100kHz/0.25V	90m	1.86	1R5
MSCD-32-1R8□-RU	1.8	M,N	100kHz/0.25V	0.11	1.80	1R8
MSCD-32-2R2□-RU	2.2	K,M,N	100kHz/0.25V	0.13	1.39	2R2
MSCD-32-2R7□-RU	2.7	M,N	100kHz/0.25V	0.14	1.32	2R7
MSCD-32-3R3□-RU	3.3	M,N	100kHz/0.25V	0.17	1.25	3R3
MSCD-32-3R9□-RU	3.9	M,N	100kHz/0.25V	0.19	1.20	3R9
MSCD-32-4R7□-RU	4.7	M,N	100kHz/0.25V	0.21	1.03	4R7
MSCD-32-5R6□-RU	5.6	M,N	100kHz/0.25V	0.22	0.91	5R6
MSCD-32-6R8□-RU	6.8	M,N	100kHz/0.25V	0.25	0.85	6R8
MSCD-32-8R2□-RU	8.2	M,N	100kHz/0.25V	0.28	0.82	8R2
MSCD-32-100□-RU	10	M	100kHz/0.25V	0.32	0.74	100
MSCD-32-120□-RU	12	M	100kHz/0.25V	0.35	0.64	120
MSCD-32-150□-RU	15	M	100kHz/0.25V	0.40	0.60	150
MSCD-32-180□-RU	18	M	100kHz/0.25V	0.48	0.54	180
MSCD-32-220□-RU	22	M	100kHz/0.25V	0.58	0.50	220
MSCD-32-270□-RU	27	M	100kHz/0.25V	0.65	0.43	270
MSCD-32-330□-RU	33	M	100kHz/0.25V	0.80	0.37	330
MSCD-32-390□-RU	39	M	100kHz/0.25V	0.90	0.36	390
MSCD-32-470□-RU	47	M	100kHz/0.25V	1.19	0.33	470
MSCD-32-560□-RU	56	M	100kHz/0.25V	1.27	0.30	560
MSCD-32-680□-RU	68	M	100kHz/0.25V	1.73	0.29	680
MSCD-32-820□-RU	82	M	100kHz/0.25V	1.99	0.25	820
MSCD-32-101□-RU	100	K,M	100kHz/0.25V	2.52	0.20	101
MSCD-32-121□-RU	120	K,M	100kHz/0.25V	2.90	0.19	121
MSCD-32-151□-RU	150	K,M	100kHz/0.25V	3.36	0.17	151
MSCD-32-181□-RU	180	K,M	100kHz/0.25V	4.03	0.17	181
MSCD-32-221□-RU	220	K,M	100kHz/0.25V	5.64	0.14	221
MSCD-32-331□-RU	330	K,M	100kHz/0.25V	9.24	0.12	331
MSCD-32-391□-RU	390	K,M	100kHz/0.25V	10.14	0.09	391
MSCD-32-471□-RU	470	K,M	100kHz/0.25V	11.48	0.08	471
MSCD-32-561-RU	560	K,M	100kHz/0.25V	19.49	0.08	561
MSCD-32-681□-RU	680	K,M	100kHz/0.25V	22.00	0.07	681
MSCD-32-821□-RU	820	K,M	100kHz/0.25V	23.98	0.06	821
MSCD-32-102□-RU	1000	K,M	100kHz/0.25V	28.80	0.05	102

※ □ specify the inductance tolerance,K(±10%),M(±20%),N(±30%)

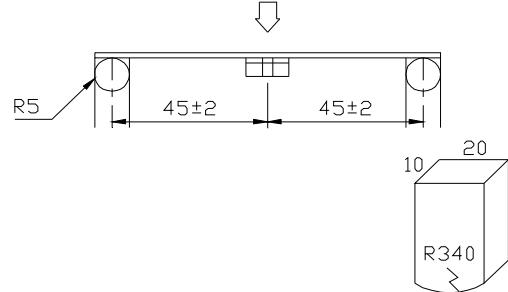
※ IDC : Based on inductance change ($\Delta L/L_0$: drop 10% Max.) @ ambient temperature 25°C and
 Based on temperature rise (ΔT : 40°C TYP.)



M A G . L A Y E R S

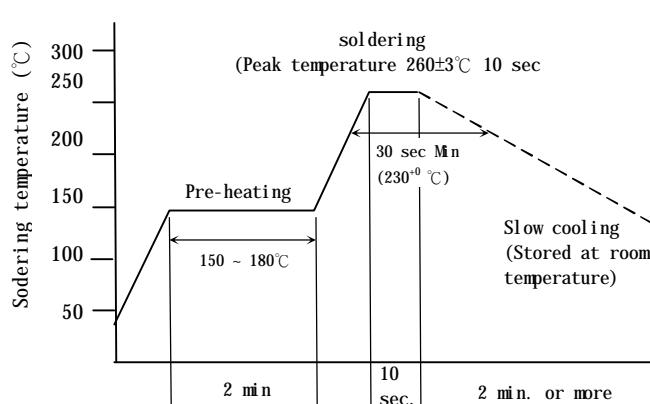
(4) RELIABILITY TEST METHOD

MECHANICAL

TEST ITEM	SPECIFICATION	TEST DETAILS
Substrate bending	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage or electrical damage.	<p>The sample shall be soldered onto the printed circuit board in figure 1 and a load applied until the figure in the arrow direction is made approximately 3mm.(keep time 30 seconds)</p> <p>PCB dimension shall the page 7/9</p> <p style="text-align: center;">F(Pressurization)</p>  <p style="text-align: center;">PRESSURE ROD figure-1</p>
Vibration	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	<p>The sample shall be soldered onto the printed circuit board and when a vibration having an amplitude of 1.52mm and a frequency of from 10 to 55Hz/1 minute repeated should be applied to the 3 directions (X,Y,Z) for 2 hours each.</p> <p>(A total of 6 hours)</p>
Solderability	New solder More than 90%	<p>Flux (rosin, isopropyl alcohol{JIS-K-1522}) shall be coated over the whole of the sample before hard, the sample shall then be preheated for about 2 minutes in a temperature of 130~150°C and after it has been immersed to a depth 0.5mm below for 3±0.2 seconds fully in molten solder M705 with a temperature of 245±5°C.</p> <p>More than 90% of the electrode sections shall be covered with new solder smoothly when the sample is taken out of the solder bath.</p>



MECHANICAL

TEST ITEM	SPECIFICATION	
Resistance to Soldering heat (reflow soldering)	<p>There shall be no damage or problems.</p>  <p>The graph shows Soldering temperature (°C) on the y-axis (50 to 300) and time on the x-axis. The Pre-heating phase rises from 50°C to 150°C (~180°C) over 2 minutes. The soldering phase peaks at 260±3°C for 10 seconds, with a minimum of 230°C for 30 seconds. The Slow cooling phase follows, stored at room temperature for 2 minutes or more.</p>	<p>Temperature profile of reflow soldering</p> <p>The specimen shall be passed through the reflow oven with the condition shown in the above profile for 1 time.</p> <p>The specimen shall be stored at standard atmospheric conditions for 1 hour, after which the measurement shall be made.</p>

ELECTRICAL

TEST ITEM	SPECIFICATION	TEST DETAILS
Insulation resistance	<p>There shall be no other damage or problems.</p>	<p>DC 100V voltage shall be applied across this sample of top surface and the terminal.</p> <p>The insulation resistance shall be more than $1 \times 10^8 \Omega$.</p>
Dielectric withstand voltage	<p>There shall be no other damage or problems.</p>	<p>AC 100V voltage shall be applied for 1 minute across the top surface and the terminal of this sample</p>
Temperature characteristics	<p>$\Delta L/L20^\circ\text{C} \leq \pm 10\%$</p> <p>0~2000 ppm/°C</p>	<p>The test shall be performed after the sample has stabilized in an ambient temperature of -20 to +85°C, and the value calculated based on the value applicable in a normal temperature and normal humidity shall be $\Delta L/L20^\circ\text{C} \leq \pm 10\%$.</p>



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ENVIROMENT CHARACTERISTICS

TEST ITEM	SPECIFICATION	
High temperature storage	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	The sample shall be left for 96 ± 4 hours in an atmosphere with a temperature of $85 \pm 2^\circ\text{C}$ and a normal humidity. Upon completion of the measurement shall be made after the sample has been left in a normal temperature and normal humidity for 1 hour.
Low temperature storage	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	The sample shall be left for 96 ± 4 hours in an atmosphere with a temperature of $-25 \pm 3^\circ\text{C}$. Upon completion of the test, the measurement shall be made after the sample has been left in a normal temperature and normal humidity for 1 hour.
Change of temperature	$\Delta L/L_0 \leq \pm 5\%$ There shall be no other damage of problems	The sample shall be subject to 5 continuos cycles, then it shall be subjected to standard atmospheric conditions for 1 hour, after which measurement shall be made.
Moisutre storage	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	The sample shall be left for 96 ± 4 hours in a temperature of $40 \pm 2^\circ\text{C}$ and a humidity(RH) of $90 \sim 95\%$. Upon completion of the test, the measurement shall be made after the sample has been left in a normal temperature and normal humidity more than 1 hour.
Test conditions : The sample shall be reflow soldered onto the printed circuit board in every test.		



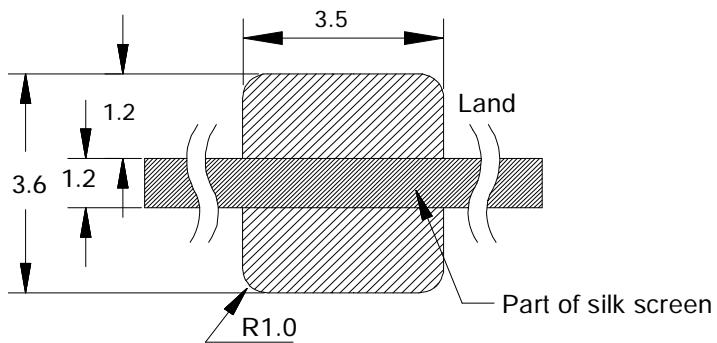
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(5) LAND DIMENSION (Ref.)

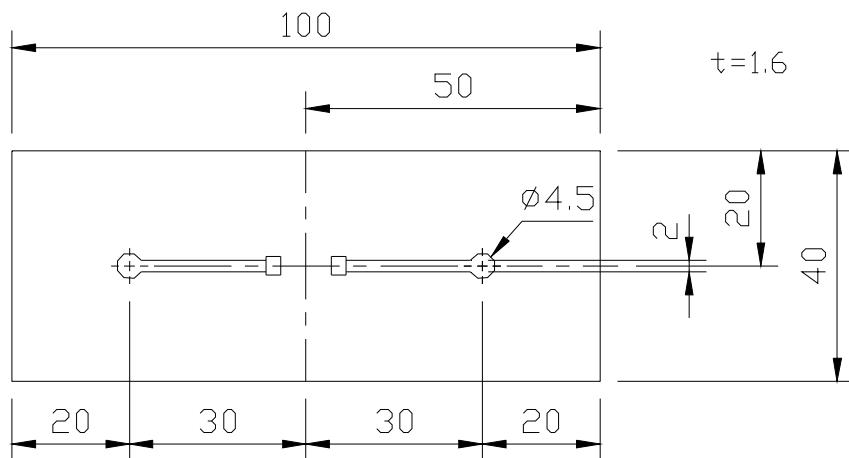
PCB: GLASS EPOXY $t=1.6\text{mm}$

(5)-1 LAND PATTERN DIMENSIONS

(STANDARD PATTERN) Unit : mm



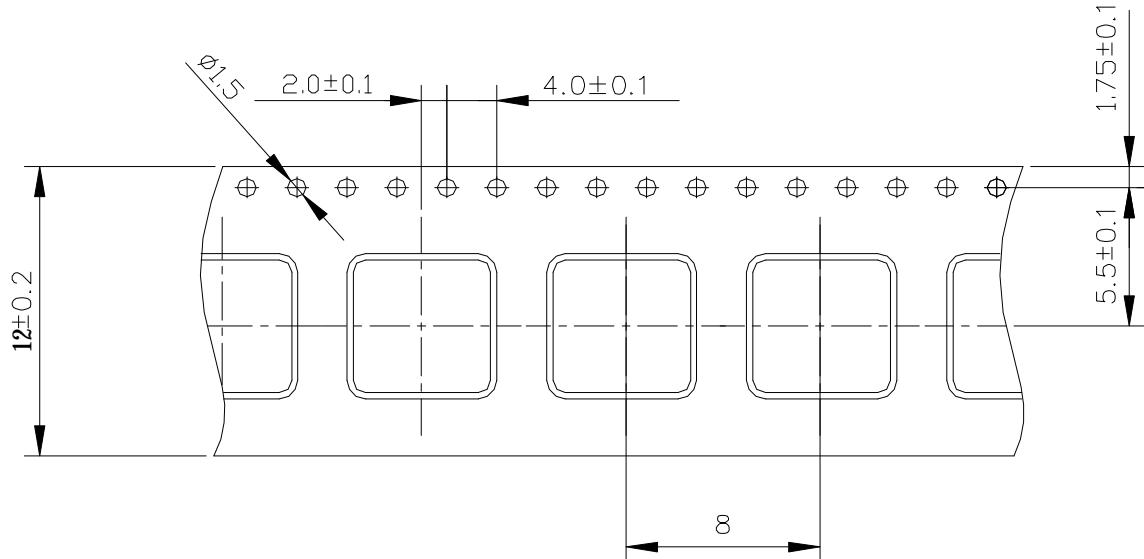
(5)-2 SUBSTRATE BENDING TEST BENDING TEST BOARD



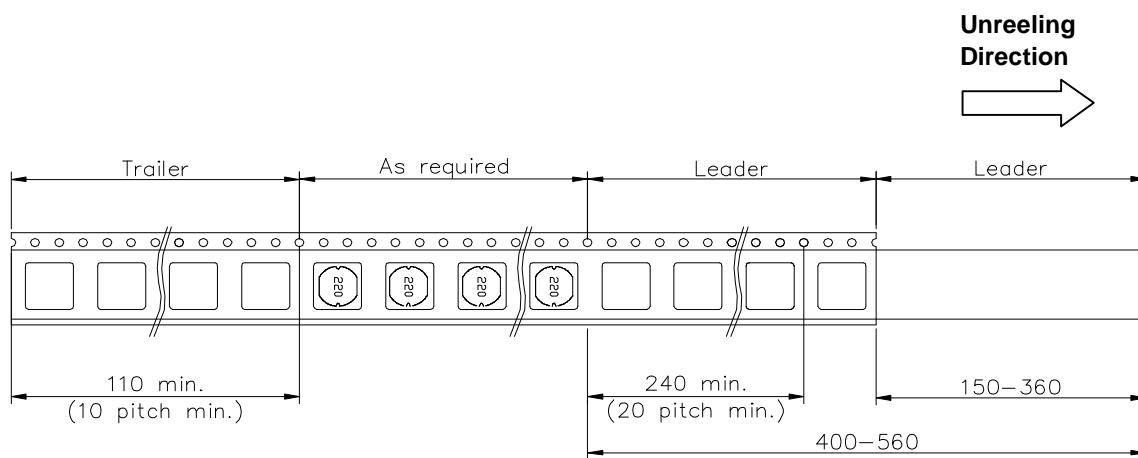
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(6) PACKAGING

(6)-1 CARRIER TAPE DIMENSIONS (mm)

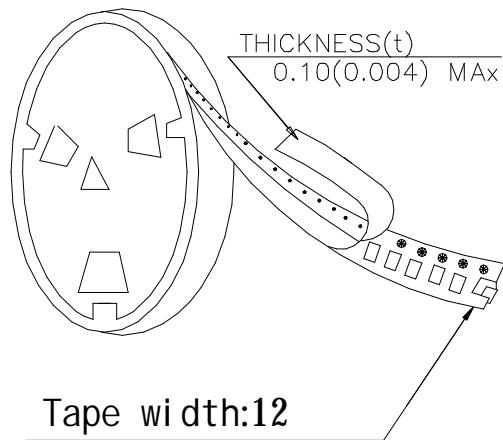
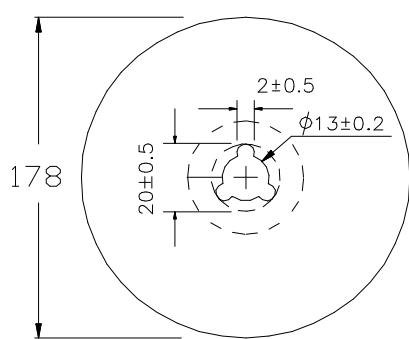


(6)-2 TAPING DIMENSIONS (mm)



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(6)-3 REEL DIMENSIONS (mm)



(6)-4 QUANTITY

1000 pcs/Reel

The products are packaged so that no damage will be sustained.



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